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an underlayer which comprises a first underlayer consisting of chromium and having a thickness of 5 to 25 nm, a second sputtered underlayer consisting of nickel and phosphorus and a third underlayer consisting of chromium and molybdenum which are formed in the described order,

wherein said second underlayer has a thickness of not less than 5nm, contains P in the concentration of 15 to 33 atom % in the NiP layer and has a mechanically textured structure having a surface roughness  $Ra_2$  in a radial direction of less than 2 nm, and said third underlayer has a thickness of not more than 60 nm and has a widened lattice spacing approaching the lattice spacing of a magnetic recording layer formed thereon, and

a magnetic recording layer which has a circumferential direction of easy magnetization and contains cobalt as a principal component thereof, and also contains chromium in an amount of at least 14 at % and platinum in an amount of at least 4 at % in combination with tantalum or tantalum and niobium.

### REMARKS

Claims 1-3, 5, 9 and 12 stand rejected under § 103 on the basis of Chen, et al. ('890), Okumura et al. ('733) and Ishikawa et al. ('021). Claim 1 has been amended to further define over the cited combination, and Applicants respectfully traverse the rejection of independent claim 1 because there is no motivation to combine or modify the cited references to obtain the present invention of amended claim 1.